

TECHNICAL SPEC FOR Thickness measurement system

System Model:
KLA UV1280

Wafer size:6/8 inch

SECS/GEM:Y

Patterned:Y

Stand-alone:Y

Handler: yes

Pre-aligner: Y

Vintage: 2000

Missing parts: none

Defected parts: none

UV1280	Metrology & Inspection	meas thickness	UV1280SE	PB5	971195UV1280SE/UV1281	2000
UV1281	Metrology & Inspection	meas thickness	UV1280	PB7	970496UV1280SE/10.000AIC Ph. 1	1997
UV1282	Metrology & Inspection	meas thickness	UV1270SE	PB5	990894UV1270SE	1999

Tool availability 2024:

